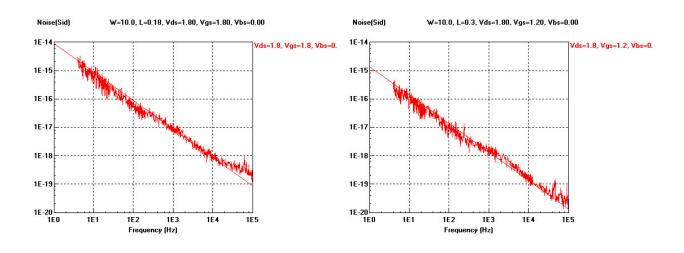


Doc.	No.: Doc. Title:	0.18um Logic Low Leakage 1P6M	Doc. Rev:	Tech Dev	Page	No.:
TD-LO18	-SP-2003	(1P5M, 1P4M) Salicide 1.8V/5.0V	4R	Rev.: 1.3	1/4	
		SPICE Model (Version 1.3)				



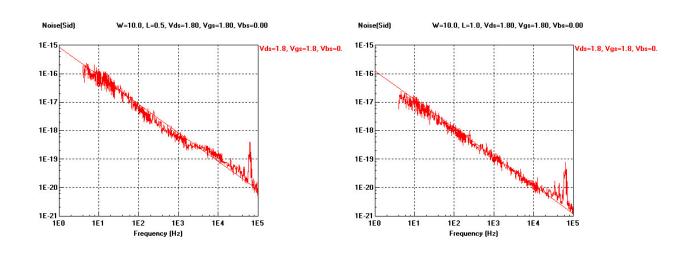
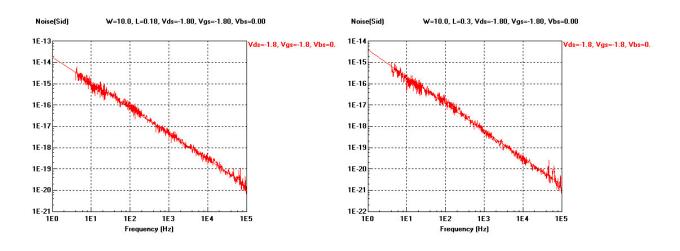


Fig.F1 The measured and simulated noise characteristics of 1.8V NMOS



Doc.	No.: Doc. Title:	0.18um Logic Low Leakage 1P6M	Doc. Rev:	Tech Dev	Page	No.:
TD-LO18-SP-	2003	(1P5M, 1P4M) Salicide 1.8V/5.0V	4R	Rev.: 1.3	2/4	
		SPICE Model (Version 1.3)				



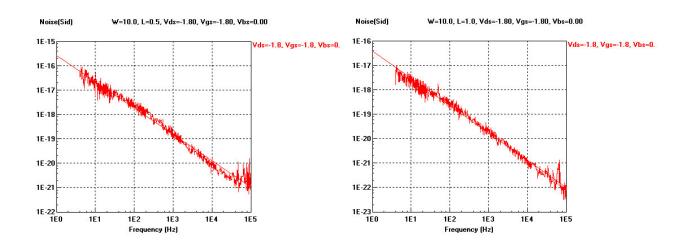
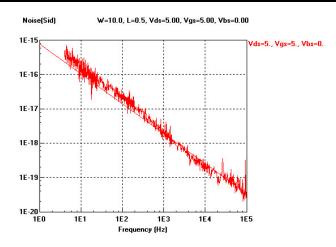
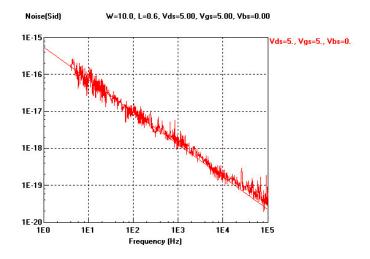


Fig.F2 The measured and simulated noise characteristics of 1.8V PMOS



Doc. TD-LO18-	No.: Doc. Title:		Doc. Rev: 4R	Tech Dev Rev.: 1.3		No.:
ID-LO10-	31 -2003	SPICE Model (Version 1.3)	710	KCV 1.3	314	





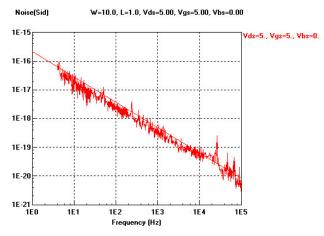


Fig.F3 The measured and simulated noise characteristics of 5V NMOS



Doc. TD-LO18-SP	No.: Doc. Title:		Tech Dev Rev.: 1.3		No.:
LO LO 10 BI	2003	SPICE Model (Version 1.3)	1.5	'' '	

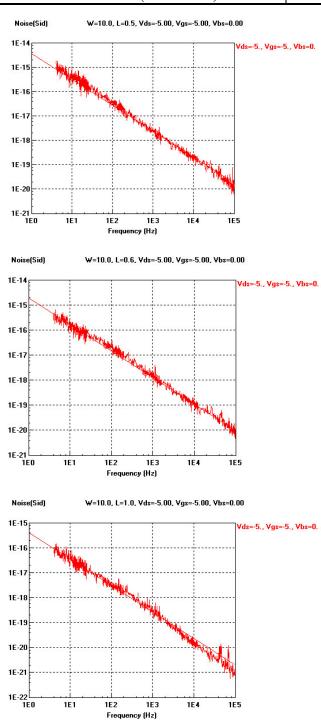


Fig.F4 The measured and simulated noise characteristics of 5V PMOS